

Achieving Software Reliability Without Breaking the Budget

Bojan Cukic

Lane Department of CSEE West Virginia University

> University of Houston September 2013



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

Software Engineering (I)maturity

- 35% of large applications are cancelled,
- 75% of the remainder run late and are over budget,
- Defect removal efficiency is only about 85%
- Software needs better measures of results and better quality control.
- Right now various methods act like religious cults more than technical disciplines.
 - Capers Jones, Feb. 3, 2012, in Data & Analysis Center for Software (DACS), LinkedIn Discussion Forum



An NSF I/UCR Center advancing ID management research

ToR

Software Engineering (I)maturity

• Major cost drivers for software in the U.S., rank order

- 1) The cost of finding and fixing bugs
- 2) The cost of cancelled projects
- 3) The cost of producing / analyzing English words
- 4) The cost of security flaws and attacks
- 5) The cost of requirements changes
- 6) The cost of programming or coding
- 7) The cost of customer support

• • •

CITeR

11) The cost of innovation and new kinds of software

12) The cost of litigation for failures and disasters

13) The cost of training and learning

14) The cost of avoiding security flaws

15) The cost of assembling reusable components

• This list is based on analysis of ~13,000 projects.

- Capers Jones, Feb. 4, 2012, in DACS

The Center for Identification Technology Research

Outline – Software Engineering as Data Science

Fault prediction

- Early in the life cycle.
- Lower the cost of V&V by directing the effort to places that most likely hide faults.

Effort prediction

- With few data points from past projects
- Problem report triage
- Summary

CITeR

The Center for Identification Technology Research



- Probability of failure given known operational usage.
 - Reliability growth
 - Extrapolates reliability from test failure frequency.
 - Applicable late in the life cycle.
 - Statistical testing and sampling
 - Prohibitively large number of test cases.
 - Formal analysis

CITeR

- Applied to software models
- All prohibitively expensive
 - -> Predict where faults hide, optimize verification.

The Center for Identification Technology Research



- Extensive research in software quality prediction.
 - Faulty modules identified through the analysis and modeling of static code metrics.
 - Significant payoff in software engineering practice by concentrating V&V resources on problem areas.

• Are all the prediction methods practical?

- Predominantly applied to multiple version systems
 - A wealth of historical information from previous versions.
- What if we are creating Version 1.0?

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

CITER



• Not as rare a problem as some tend to believe.

- Customized products are developed regularly.
- One of a kind applications:

ITeR

- Embedded systems, space systems, defense applications.
- Typically high dependability domains.
- NASA MDP data sets fall into this category.

Labeling modules for fault content is COSTLY!

- The fewer labels needed to build a model, the cheaper the prediction task.
 - The absence of problem report does not imply fault free module.
- Standard fault prediction literature assumes *massive* amounts of labeled data available for training.

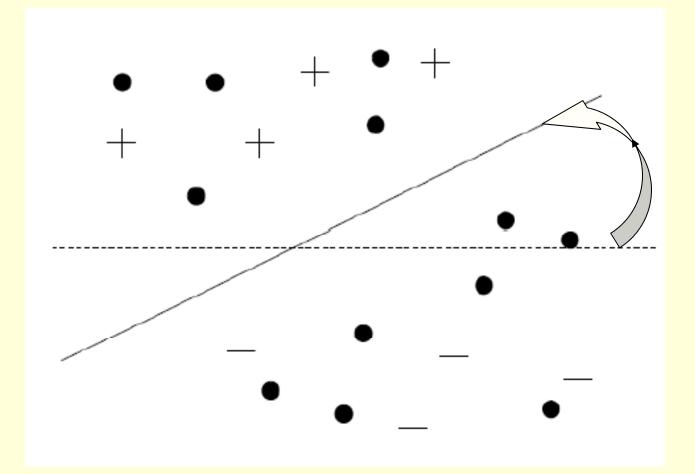


ToR

- How much data does one need to build a fault prediction model?
 - What happens when most modules do not have a label?
- Explore suitable machine learning techniques and compare results with previously published approaches.
 - Semi supervised learning (SSL).
 - An intermediate approach between supervised and unsupervised learning.
 - Labeled and unlabeled data used to train the model
 - No specific assumptions on label distributions.







The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

CITeR



ITeR

- Iteratively train a supervised learning algorithm from "currently labeled" modules.
 - Predict the labels of unlabeled modules.
 - Migrate instances with *"high confidence"* predictions into the pool of labeled modules (FTcF algorithm).
 - Repeat until all modules labeled.
- Large number of independent variables (>40).
 - Dimensional reduction (not feature selection).
 - Multidimensional scaling as the data preprocessing technique.





CITeR

A variant of self-training approach and Yaworski's algorithm.

Pre-processing Step:MDS	
1: Input: X, Y_l, d_m	
2: $d = tune.MDS(X_l, Y_l, d_m)$	
3: $Z = MDS(X, d)$	
4: Output: Z	
SSL Learning Step: FTcF	
1: Input: Z, Y_l	
2: Initialization: $D_l = (Z_l, Y_l), \mathbf{u} = u$	An unlabeled module
3: loop until $ u \to 0$:	may change the label
4: Fit $\hat{Y}_u = \phi_{D_l}(Z_u)$	in each iteration
5: Take u' confident cases from Z_u	
6: Updating: $Z_l = Z_{l+u'}, Z_u = Z_{u-u'},$	
$Y_{l} = Y_{l} + \hat{Y}_{u'}$, and $D_{l} = (Z_{l}, Y_{l})$	Base learner φ :
7: End loop	Random forest
8:Output: \hat{Y}_{u}	- robust to noise

The Center for Identification Technology Research



Fault Prediction Data Sets

Data	Size#	% faulty	project description	language
KC1	2109	13.9%	Storage management for ground data	С++.
PC3	1563	10.43%	Flight software for earth orbiting satellite	С
PC4	1458	12.24%	Flight software for earth orbiting satellite	С
PC1	1109	6.59%	Flight software from an earth orbiting satellite	С

• Large NASA MDP projects (> 1,000 modules)

The Center for Identification Technology Research

CITER The Center for In An NSF I/UCR Center advancing ID management research



- Compare the performance of four fault prediction approaches, all using RF as the base learner:
 - Supervised learning (SL)
 - Supervised learning with dimensionality reduction (SL.MDS)
 - Semi-supervised learning (SSL)
 - Semi-supervised learning w dimensionality reduction (SSL.MDS)
- Assume 2% 50% of modules are labeled.
 - Randomly selected, 10 times.

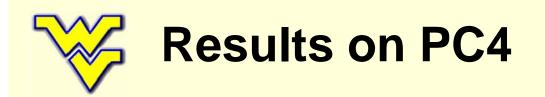
ITAR

• Performance evaluation: Area under ROC, PD

$$-\mathbf{PD} = \frac{|\hat{Y}_U \ge \tau|}{|Y_U = 1|} \quad \tau = \{0.1, 0.5, 0.75\}$$

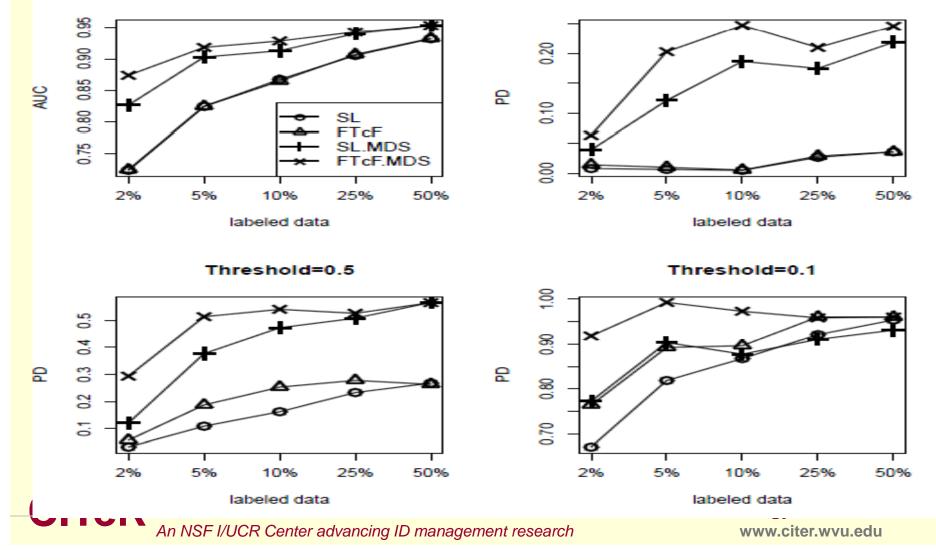
The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research



AUC

Threshold=0.75





CITek

Comparing Techniques: AUC

	Table 2: AUC for the four data sets							
Data	size of L	SL	FTcF	SL.MDS	FTcF.MDS			
PC1	2%	0.6733	0.6677	0.8379	0.8536			
	5%	0.7122	0.7087	0.8719	0.8889			
	10%	0.7721	0.7806	0.9166	0.9253			
	25%	0.8484	0.8464	0.9353	0.9356			
	50%	0.8687	0.8728	0.9425	0.9434			
PC3	2%	0.7053	0.7096	0.7550	0.7841			
	5%	0.7386	0.7355	0.8494	0.8860			
	10%	0.7512	0.7573	0.8829	0.9024			
	25%	0.7922	0.7981	0.9103	0.9183			
	50%	0.8199	0.8246	0.9267	0.9260			
PC4	2%	0.7235	0.7246	0.8264	0.8737			
	5%	0.8242	0.8243	0.9029	0.9183			
	10%	0.8672	0.8644	0.9129	0.9285			
	25%	0.9054	0.9069	0.9403	0.9430			
	50%	0.9321	0.9327	0.9538	0.9535			
KC1	2%	0.7374	0.7295	0.6793	0.7382			
	5%	0.7404	0.7476	0.7437	0.7477			
	10%	0.7635	0.7693	0.7728	0.7831			
	25%	0.7794	0.7897	0.7938	0.7850			
	50%	0.8043	0.8108	0.8134	0.8030			

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research



Comparing Techniques: PD

Table 5: PD with threshold=0.1 for the four data sets

3613					
Data	size of L	SL	FTcF	SL.MDS	FTcF.MDS
PC1	2%	0.6365	0.7108	0.8027	0.8770
	5%	0.6662	0.7394	0.8648	0.9592
	10%	0.7138	0.8092	0.8800	0.9631
	25%	0.8204	0.8571	0.8796	0.9449
	50%	0.8476	0.8667	0.9095	0.9238
PC3	2 %	0.6395	0.7758	0.7248	0.8771
	5%	0.6693	0.7497	0.8196	0.9725
	10 %	0.6910	0.7903	0.8366	0.9538
	25%	0.7851	0.8587	0.8579	0.9240
	50%	0.8085	0.8622	0.8780	0.9098
PC4	2 %	0.6710	0.7642	0.7727	0.9182
	5%	0.8187	0.8924	0.9035	0.9930
	10%	0.8677	0.8963	0.8774	0.9732
	25%	0.9211	0.9606	0.9106	0.9585
	50%	0.9538	0.9604	0.9311	0.9604
KC1	2%	0.5489	0.7249	0.5938	0.7969
	5%	0.6067	0.6876	0.7130	0.8190
	10%	0.6773	0.7461	0.7421	0.8043
	25%	0.6773	0.7473	0.7260	0.7623
	50%	0.7368	0.7695	0.7505	0.7618



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research



- H_0 : There is no difference between the 4 algorithms across all data sets
- H_a: Prediction performance of at least one algorithm is significantly better than the others across all data sets

P-value from ANOVA measures evidence against **H**₀

Which approaches differ significantly?

Use post-hoc Tukey's "honestly significant difference (HSD)"

Table 2: P-value of ANOVA	test on varied size of					
labeled data for all performance measures						

size of L	AUC	PD(0.75)	PD(0.5)	PD(0.1)
2%	0.03795	0.00054	0.00052	0.00100
5%	0.05688	0.000105	1.09E-06	0.01011
10%	0.08185	5.72E-07	3.97E-06	0.02952
25%	0.33810	1.44E-05	0.00033	0.53151
50%	0.49175	0.00062	0.00433	0.85391

Table 4: Significance comparison of PD(0.1)

	SL	FTcF	SL.MDS
FTcF	none		_
SL.MDS	none	none	
FTcF.MDS	2%, 5%, 10%	2%	2%

The Center for Identification Technology Research

CITER The Center for I An NSF I/UCR Center advancing ID management research



• Lessman (TSE 2008) and Menzies (TSE 2007) offer benchmark performance for NASA MDP data sets

- Lessman et al. on 66% of the data, Menzies trains on 90%,

AUC	•			1 0
Data sets	Size of L	SL	FTcF.MDS	Lessmann [18]
PC1	2%	0.67	0.85	
	5%	0.71	0.89	
	10%	0.77	0.93	
	25%	0.85	0.94	
	50%	0.87	0.94	0.9
PC3	2%	0.71	0.78	
	5%	0.74	0.88	
	10%	0.75	0.90	
	25%	0.79	0.91	
	50%	0.82	0.93	0.82
PC4	2%	0.72	0.87	
	5%	0.82	0.92	
	10%	0.87	0.93	
	25%	0.91	0.94	
	50%	0.93	0.95	0.97
KC1	2%	0.74	0.74	
	5%	0.74	0.74	
	10%	0.76	0.78	
	25%	0.78	0.79	
	50%	0.80	0.80	0.78

Table 11: Comparison of results with [18] using

Table 10: Comparison of results with [19]							
Data sets	Size of L	SL	FTcF.MDS	Menzies [19]			
PC1	2%	0.45	0.73				
(PF=0.17)	5%	0.46	0.80				
-	10%	0.53	0.85				
	25%	0.66	0.88				
	50%	0.74	0.91	0.48			
PC3	2%	0.66	0.77				
(PF=0.35)	5%	0.73	0.90				
	10%	0.74	0.92				
	25%	0.81	0.94				
	50%	0.85	0.95	0.8			
PC4	2%	0.62	0.89				
(F=0.29)	5%	0.79	0.81				
	10%	0.86	0.97				
	25%	0.94	0.98				
	50%	0.98	0.99	0.98			

Center for	^r Identification	Technology	Research

ment research



- The lack of training data not an issue.
- Eclipse data set

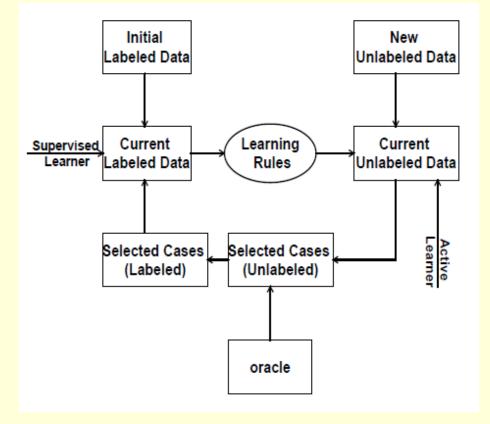
Release	packages/files	% with defects	metrics
2.0	377 / 6729	50.4% / 14.5%	41/32
2.1	434 / 7888	44.7% / 10.8%	41/32
3.0	661 / 10593	47.4% /14.8%	41/32

- Active instead of supervised learning
 - Characteristics of faults change between the successive versions.

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research





In each iteration, 1% of the modules is "labeled" by the "oracle".

"Oracle" → Software V&V Engineer

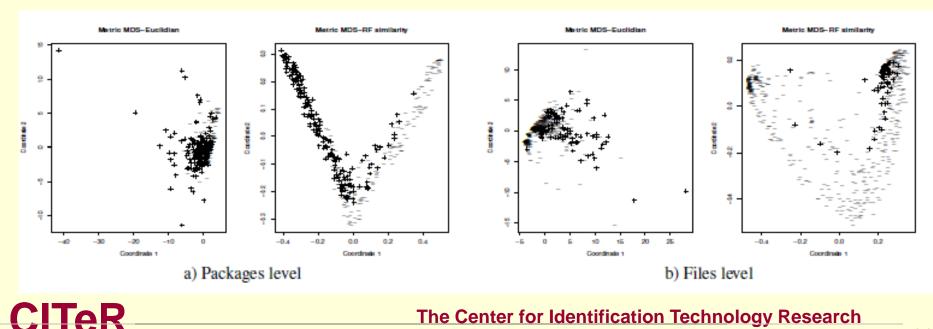
The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

CITeR

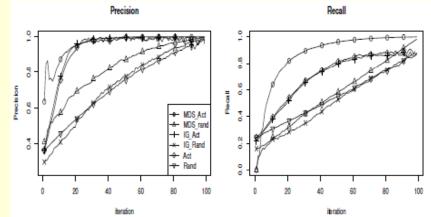
Dimensionality Reduction

- Too many highly correlated software metrics! •
- Multi-dimensional scaling (MDS) lacksquare
 - A nonlinear optimization.
 - Finds embeddings s.t. similarities are preserved.
 - Similarity measure matters random forest similarity

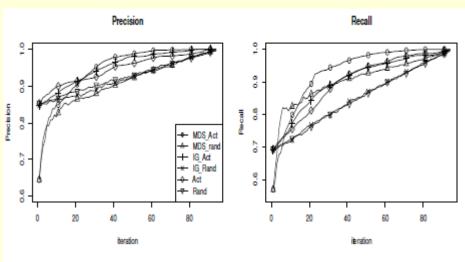


The Center for Identification Technology Research





Accuracy







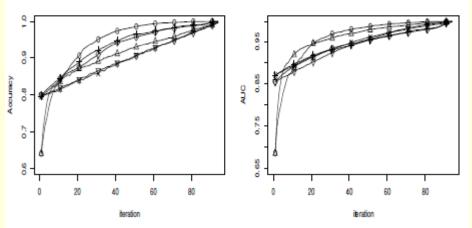


Figure 7: Defect prediction in release 2.1 from 2.0 (files)

AUC 5 0.0

> 4 ó 4

> > 0

20

Figure 6: Defect prediction in release 3.0 from 2.0 and 2.1 (packages)



8

8 ö

ó

0

20

40

iteration

80

100

The Center for Identification Technology Research An NSF I/UCR Center advancing ID management research

100

80

AUC

iteration

Statistical Significance

Table 10: Post-hoc test for performance differences between the six active learning approaches at their 30th iteration (1 : $MDS_Act, 2$: $MDS_rand, 3$: $IG_Act, 4$: $IG_rand, 5$: Act, 6 : Rand). " \checkmark " stands for statistically significant difference between two approaches. "x" stands for no significant difference detected between the two approaches.

Prediction from	Predicting for	Methods Compared		Packag	e level			File l	evel	
			Precision	Recall	Accuracy	AUC	Precision	Recall	Accuracy	AUC
release 2.0	release 2.1	1-2	✓	\checkmark	1	\checkmark	✓	\checkmark	×	\checkmark
		1-3	\checkmark	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1–4	1	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		1-5	✓	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1-6	1	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		3–4	\checkmark	\checkmark	\checkmark	X	✓	\checkmark	\checkmark	\checkmark
		3–5	x	X	X	\checkmark	x	X	X	X
		3-6	1	X	\checkmark	X	✓	\checkmark	\checkmark	X
		5-6	\checkmark	\checkmark	\checkmark	X	✓	\checkmark	\checkmark	X
release 2.0 & 2.1	release 3.0	1-2	✓	\checkmark	~	\checkmark	 ✓ 	\checkmark	\checkmark	\checkmark
		1-3	x	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1–4	\checkmark	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		1-5	\checkmark	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1-6	✓	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		3–4	✓	\checkmark	\checkmark	X	✓	\checkmark	\checkmark	X
		3–5	x	X	\checkmark	X	x	X	X	X
		3–6	\checkmark	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	X
		5-6	\checkmark	\checkmark	~	\checkmark	✓	\checkmark	\checkmark	X
release 2.1	release 3.0	1-2	✓	\checkmark	\checkmark	X	✓	\checkmark	\checkmark	\checkmark
		1–3	x	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1–4	✓	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		1–5	\checkmark	\checkmark	\checkmark	\checkmark	x	\checkmark	\checkmark	\checkmark
		1–6	\checkmark	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark
		3-4	✓	\checkmark	\checkmark	x	✓	\checkmark	\checkmark	X
		3–5	✓ _	x	x	\checkmark	x	x	x	~
		3-6	\checkmark	\checkmark	\checkmark	X	✓	\checkmark	\checkmark	\checkmark
		5-6	✓	\checkmark	\checkmark	\checkmark	✓	\checkmark	\checkmark	\checkmark



An NSF I/UCR Center advancing ID management research

CITeR



- Fault prediction from few data points is feasible
 - A few extra points in large projects help the prediction too.
- Unlabeled data naturally occurs in fault prediction.
 - Embrace it!

CITeR

• While not predicting reliability, these techniques optimize V&V expenditure.

The Center for Identification Technology Research

Outline – Software Engineering as Data Science

Fault prediction

- Early in the life cycle.
- Lower the cost of V&V by directing the effort to places that most likely hide faults.

Effort prediction

- With few data points from past projects.
- Problem report triage
 - Minimize human involvement.
- Summary

CITeR

The Center for Identification Technology Research

Software Effort Estimation (SEE)

- Supervised learning predominant in the literature
 - Independent variables
 - E.g. *metrics* defining completed software projects.
 - Dependent variables
 - E.g. *labels (effort values)* from past projects.

Collecting metrics is relatively easy, but

- The collection of labels is very costly [1].
- In some cases actual effort data may not even exist.
- Data starved problems!

CITeR

The Center for Identification Technology Research

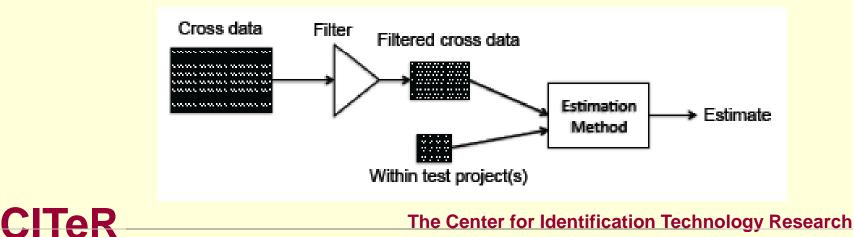
An NSF I/UCR Center advancing ID management research

Proposition of Crosscompany Data

- When effort data from past is not available
 - Use effort examples from others (cross-company data)
 - Use cross-company data for training

• Is it relevant for your project?

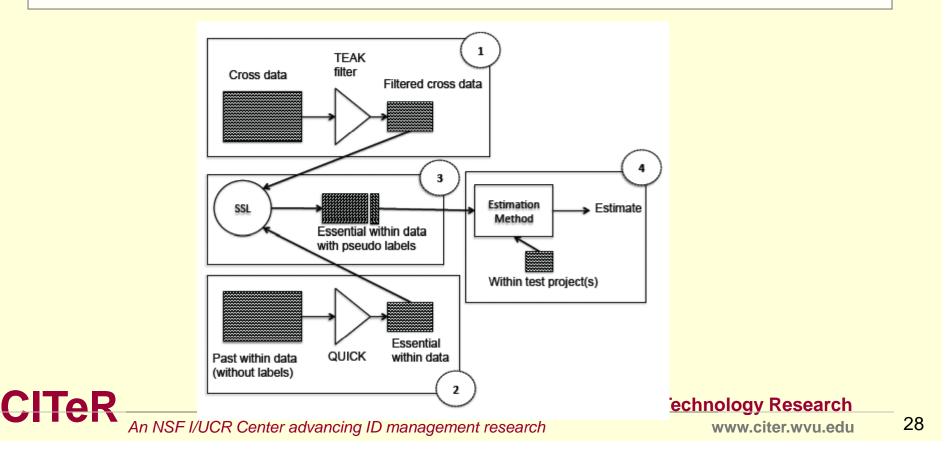
- Transferring all project examples is not a good idea.
- Select instances that appear to be projects "similar" to the one at hand.



An NSF I/UCR Center advancing ID management research



 The goal is to enable effective prediction in cases when doing it with other methods would not be feasible.





Synergy, compared to within/cross-company learning over 20 runs (hence 2x20 = 40 total comparisons) in terms of win, tie, loss

- Cases of losses are highlighted with gray

Dataset	MAR			MMRE			MdMRE			Pred(25)			MBRE			MIBRE			MMER		
	W	Т	L	W	Т	L	W	Т	L	W	Т	L	W	Т	L	W	Т	L	W	Т	L
cocomo81e	0	39	1	2	32	6	0	32	8	1	32	7	0	25	15	0	25	15	0	26	14
cocomo81o	0	27	13	0	31	9	0	31	9	0	31	9	0	26	14	0	26	14	0	27	13
cocomo81s	0	40	0	0	39	1	0	39	1	0	39	1	0	40	0	0	40	0	0	40	0
nasa93_center_1	0	38	2	0	39	1	0	39	1	0	39	1	0	38	2	0	38	2	1	39	0
nasa93_center_2	1	38	1	1	38	1	1	38	1	1	38	1	1	39	0	1	39	0	1	38	1
nasa93_center_5	0	40	0	1	38	1	0	38	2	0	38	2	6	29	5	6	29	5	7	28	5
desharnaisL1	0	38	2	0	32	8	0	32	8	0	32	8	0	28	12	0	28	12	0	28	12
desharnaisL2	0	38	2	0	37	3	0	37	3	0	37	3	0	38	2	0	38	2	0	38	2
desharnaisL3	0	31	9	0	24	16	0	24	16	0	24	16	0	31	9	0	31	9	0	40	0
finnishAppType1	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0
finnishAppType2345	0	38	2	0	38	2	0	38	2	0	38	2	0	39	1	0	39	1	1	38	1
kemererHardware1	0	40	0	0	39	1	0	39	1	0	39	1	0	40	0	0	40	0	0	40	0
kemererHardware23456	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0
maxwellAppType1	0	31	9	0	33	7	0	33	7	0	33	7	0	32	8	0	32	8	0	33	7
maxwellAppType2	0	39	1	0	39	1	0	39	1	0	39	1	0	37	3	0	37	3	0	35	5
maxwellAppType3	0	36	4	1	36	3	0	36	4	1	36	3	0	36	4	0	36	4	0	38	2
maxwellHardware2	0	35	5	0	38	2	0	38	2	0	38	2	0	34	6	0	34	6	0	34	6
maxwellHardware3	0	40	0	0	36	4	0	36	4	0	36	4	0	35	5	0	35	5	0	36	4
maxwellHardware5	0	36	4	0	40	0	0	40	0	0	40	0	0	40	0	0	40	0	0	39	1
maxwellSource1	0	39	1	0	37	3	0	37	3	0	37	3	0	38	2	0	38	2	0	39	1
maxwellSource2	0	40	0	0	33	7	0	33	7	0	33	7	0	27	13	0	27	13	0	26	14

The Center for Identification Technology Research

CITER The Center for In An NSF I/UCR Center advancing ID management research



Fully automated approach

- Experts not involved until the estimate is generated.
- Cross company estimates created from publicly available data

- No collection cost.

TOR

- Effort estimates can be interpreted through their similarity to local projects.
 - Cross company learning imposes the risk that estimates cannot be easily understood when they are applied to the project.

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

30

Outline – Software Engineering as Data Science

Fault prediction

- Early in the life cycle.
- Lower the cost of V&V by directing the effort to places that most likely hide faults.

Effort prediction

- With few data points from past projects.
- Problem report triage
 - Minimize human involvement.
- Summary

CITeR

The Center for Identification Technology Research



CITeR

Motivation

- Automated analysis of text-based software documents is difficult.
 - Volume
 - Open source projects average 300 400 newly submitted reports per day.
 - Firefox alone has over 120,000 problem reports associated with it, to date.
 - Mozilla has over 700,000 problem reports since 1998
 - Variability, diversity
 - An average problem report in Firefox contains 60-140 words
 - There are over 40,000 users submitting problem reports to the Firefox project

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research



• Reports can be either:

- Primary describing novel and unknown problems
- Duplicates describe previously reported problems

• Triager:

- A person responsible for determining whether a report is "Primary" or "Duplicate" and assigning it to the appropriate developer
- In open source, triagers are Mozilla staffers or volunteers
 - The development team can veto the decision of a volunteer triager.



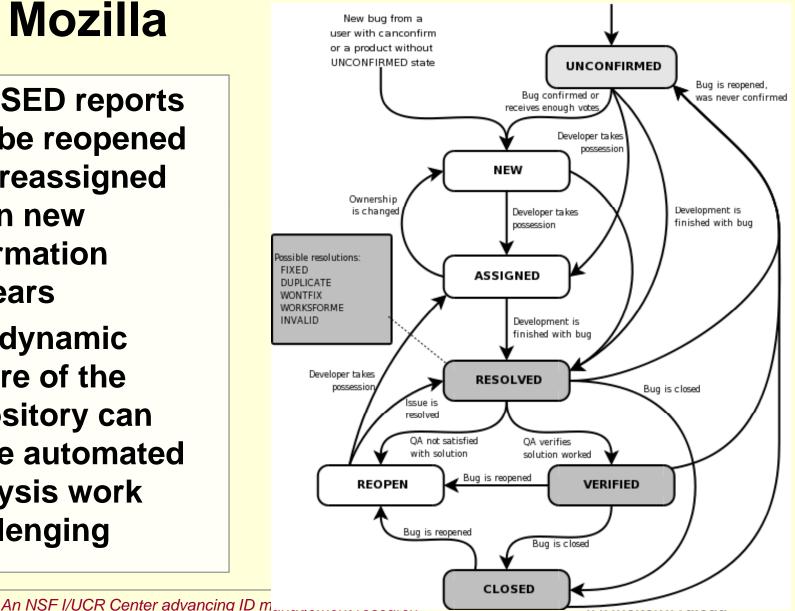
The Center for Identification Technology Research



Life cycle of a bug report in Mozilla

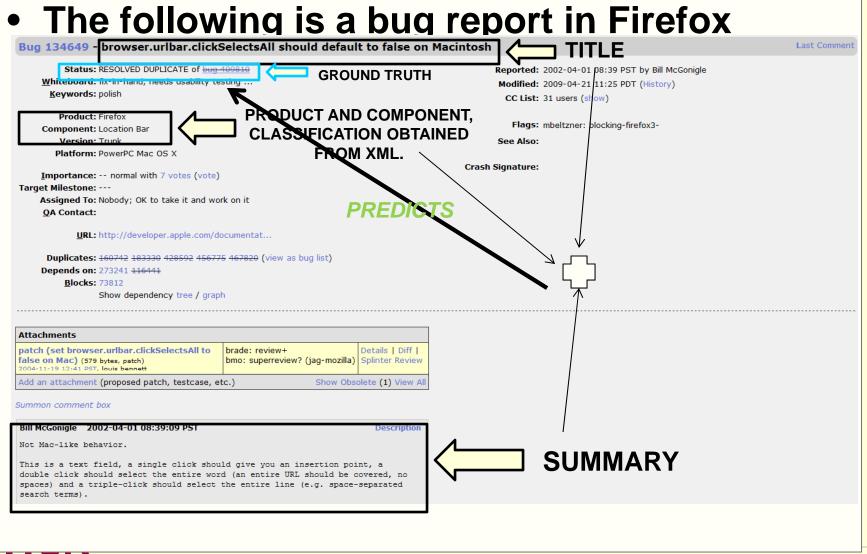
- **CLOSED** reports lacksquarecan be reopened and reassigned when new information appears
- The dynamic lacksquarenature of the repository can make automated analysis work challenging

ITeR





Sample Bug Report



An NSF I/UCR Center advancing ID management research

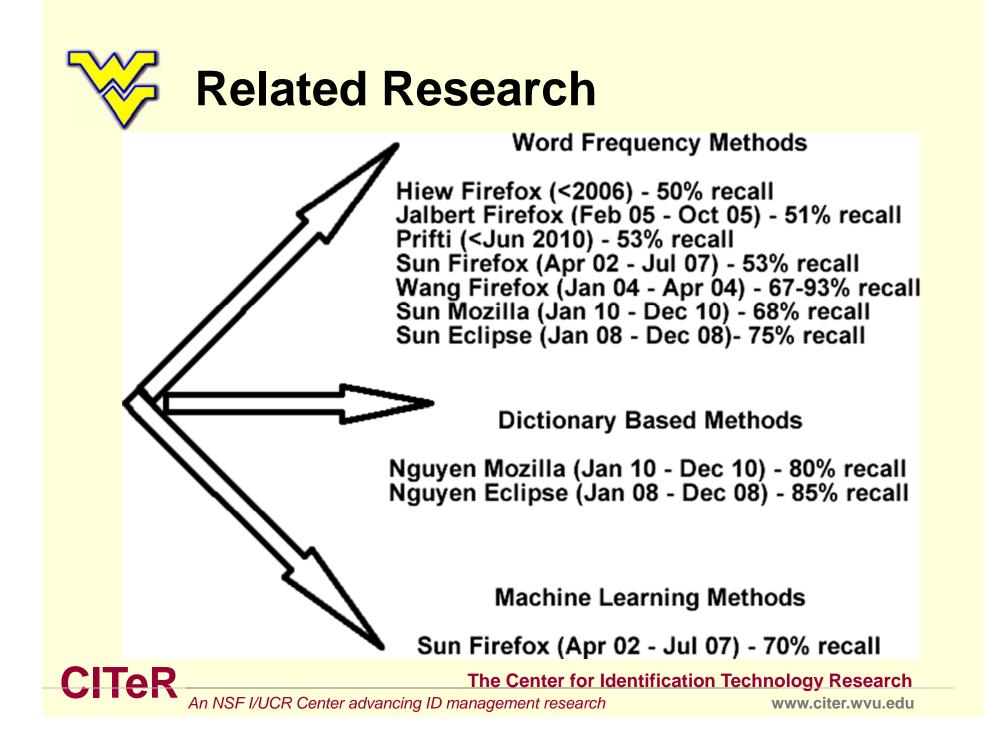


	Total Number of Problem Reports	111,206
	Total Number of Duplicates	31,034
	Total Number of Detectable Duplicates	25,085
	Duplicates Within Nearest 15,000 Groups	24,255
Firefox	Percentage of Dataset Comprised of Duplicates	28%
	Number of Duplicate Groups	12,268
	Number of Duplicate Groups with 1 Duplicate	7,492
	Number of Primaries with No Duplicates	67,904
	Ratio of Duplicate Groups to Duplicates	2.53



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research





- Develop an effective automated (or semi automated) technique to detect similar reports.
 - Can we develop a better word weighting scheme that places emphasis on intra group similarity?
 - Apply string matching to detect similar problem reports
- Must be scalable, apply to small as well as to very large issue report data sets.

The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

CITeR

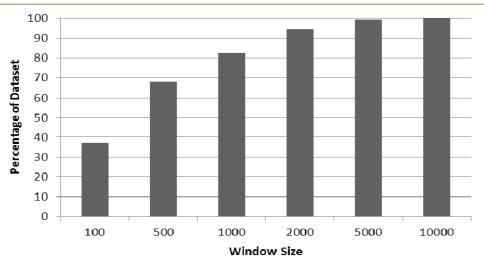


Use report's Title and Summary for analysis

Pre-processing issue reports

- Tokenize, stem, remove non essential stop words
- Combine 24 similarity measures into a multilabel classifier
 - Cosine similarity with group centroids.
 - Longest common subsequence.
- Time window

CITeR



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

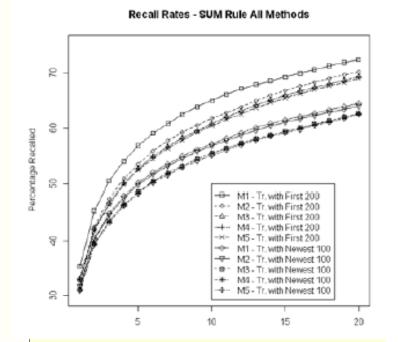


CITeR

Multi-label classification

• MULAN

- Similarity measure match scores, reports since the last duplicate (or prime), title/summary size...
- Classification indicates trust in the label correctness for each of the 24 measures
- Generate unified top 20
 match list



The Center for Identification Technology Research



Research problem open to advancement

- Continual development of alternative approaches
- Evaluation on the largest and most complicated open source repositories...

Upcoming work

- "social network" analysis of the bug reports
- Automated detection of primary reports



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research

Outline – Software Engineering as Data Science

Fault prediction

- Early in the life cycle.
- Lower the cost of V&V by directing the effort to places that most likely hide faults.

Effort prediction

- With few datProblem report triage
- a points from past projects.
- Minimize human involvement.

Summary

CITeR

The Center for Identification Technology Research



ITeR

- Software quality remains a research area with many challenges.
 - Expensive consequences of faults.
 - Imperfect software requirements, derivation, construction...
- Data analytics guide practitioners in decision making
 - Emerging as the key analysis technique.
 - Intuitively guide verification activities.

The Center for Identification Technology Research



- Empirical evaluation remains the key to improvement
 - Expanded list of artifacts: code, documentation, execution traces...
 - Realism in experiments.
- Potential for significant savings in software engineering processes
 - A major shift in software quality research.



The Center for Identification Technology Research



Thank You

Questions?



The Center for Identification Technology Research

An NSF I/UCR Center advancing ID management research